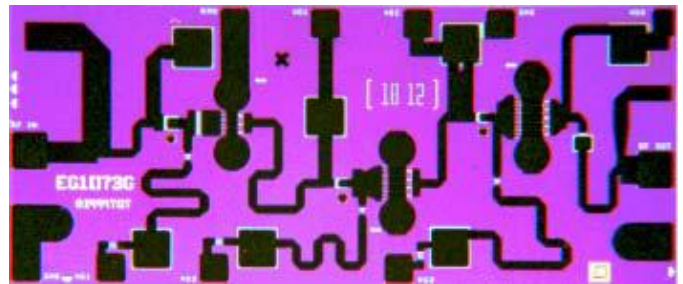


Applications

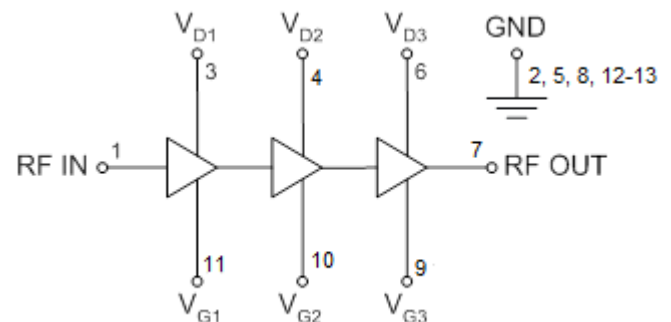
- Point-to-Point Radio
- Point-to-Multipoint Communications



Product Features

- 0.25 μm pHEMT Technology
- 22 dB Nominal Gain
- 25 dBm Nominal P_{OUT} at P1dB
- Bias: 5 to 7 V at 220 mA
- Chip Dimensions: 2.55 x 1.15 mm

Functional Block Diagram



General Description

The TriQuint TGA1073G-SCC is a three stage MPA MMIC design using TriQuint's proven 0.25 μm Power pHEMT process. The TGA1073G-SCC is designed to support a variety of millimeter wave applications including point-to-point digital radio and point-to-multipoint communications.

The three stage design consists of a 200 μm input device driving a 480 μm interstage device followed by an 800 μm output device.

The TGA1073G-SCC provides 25 dBm nominal output power at 1 dB compression across 19 to 27 GHz. Typical small signal gain is 22 dB.

The TGA1073G-SCC requires minimum off-chip components. Each device is 100% DC and RF tested on-wafer to ensure performance compliance. The device is available in chip form.

Pin Configuration

Pin No.	Label
1	RF IN
2, 5, 8, 12-13	GND
3	V_{D1}
4	V_{D2}
6	V_{D3}
7	RF OUT
9	V_{G3}
10	V_{G2}
11	V_{G1}

Ordering Information

Part No.	ECCN	Description
TGA1073G-SCC	EAR99	19 to 27 GHz Medium PA

Absolute Maximum Ratings

Parameter	Rating
Positive Supply Voltage (V^+) ⁽³⁾	8 V
Positive Supply Current (I^+) ⁽¹⁾⁽³⁾	296 mA
Negative Supply Current (I^-) ⁽¹⁾	8.8 mA
Input Continuous Wave Power (P_{IN}) ⁽³⁾	18.2 dBm
Power Dissipation (P_D) ⁽²⁾⁽³⁾	1.32 W
Mounting Temperature (30 seconds)	320°C
Storage Temperature (T_{STG})	-65 to 150°C

Operation of this device outside the parameter ranges given above may cause permanent damage.

Notes:

1. Total current for all stages.
2. When operated at this bias condition with a baseplate temperature of 55°C, the median lifetime (T_M) is 1×10^6 hours.
3. Combinations of supply voltage, supply current, input power, and output power shall not exceed P_D .

Recommended Operating Conditions

Parameter	Min	Typ	Max	Units
Operating Channel Temperature (T_{CH}) ⁽¹⁾⁽²⁾		200		°C

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

Notes:

1. These ratings apply to each individual FET.
2. Junction operating temperature will directly affect the device median lifetime (T_M). For maximum life, it is recommended that junction temperatures be maintained to the lowest possible levels.

DC Electrical Specifications

Test conditions unless otherwise noted: STD, 25°C Nominal

Parameter	Min	Typ	Max	Units
I_{DSS3}	80		376	mA
G_{M3}	176		424	mS
$ V_{P1} $ ⁽¹⁾	0.5		1.5	V
$ V_{P2} $ ⁽¹⁾	0.5		1.5	V
$ V_{P3} $ ⁽¹⁾	0.5		1.5	V
$ V_{BVG D1} $ ⁽¹⁾	11		30	V
$ V_{BVG S1} $ ⁽¹⁾	11		30	V

Notes:

1. V_P , $V_{BVG D}$, and $V_{BVG S}$ are negative.
2. The measurement conditions are subject to change at the manufacturer's discretion (with appropriate notification to the buyer).

RF Electrical Specifications

Test conditions unless otherwise noted: $T_A = 25^\circ\text{C}$, Nominal, $V_D = 6\text{ V}$, $I_D = 220\text{ mA}$.

Test	Conditions	Min	Typ	Max	Units
Small-Signal Gain Magnitude ⁽¹⁾	19 GHz 20 to 25 GHz	16 19	20 23		dB
Power Output at 1 dB Gain Compression	20 GHz 22 GHz 23.5 GHz	21 24 24	23 25 26		dBm
Input Return Loss Magnitude ⁽¹⁾	19 to 25 GHz		-20		dB
Output Return Loss Magnitude ⁽¹⁾	19 to 25 GHz		-15		dB
Output Third Order Intercept ⁽²⁾			32		dBm

Notes:

- RF probe data is taken at 1 GHz steps.
- Minimum output third-order-intercept (OTOI) is generally 6 dB minimum above the 1 dB compression point (P1dB). Calculations are based on standard two-tone testing with each tone approximately 10 dB below the nominal P1dB. Factors that may affect OTOI performance include device bias, measurement frequency, operating temperature, output interface, and output power level for each tone.

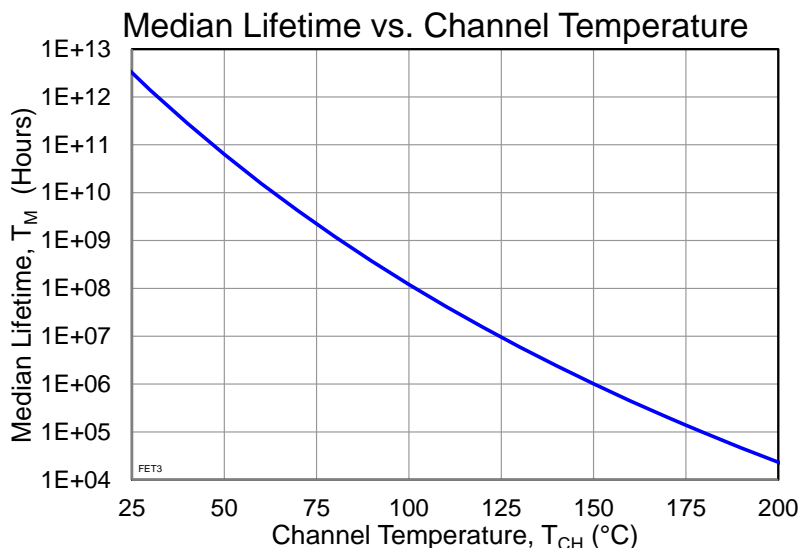
Thermal and Reliability Information

Parameter	Condition	Rating
Thermal Resistance (θ_{JC}) ⁽¹⁾	$V_D = 6\text{ V}$, $I_D = 220\text{ mA}$, $P_{DISS} = 1.32\text{ W}$	71.7°C/W
Channel Temperature (T_{CH})		149.6°C
Median Lifetime (T_M)		1.0 x 10 ⁶ Hours

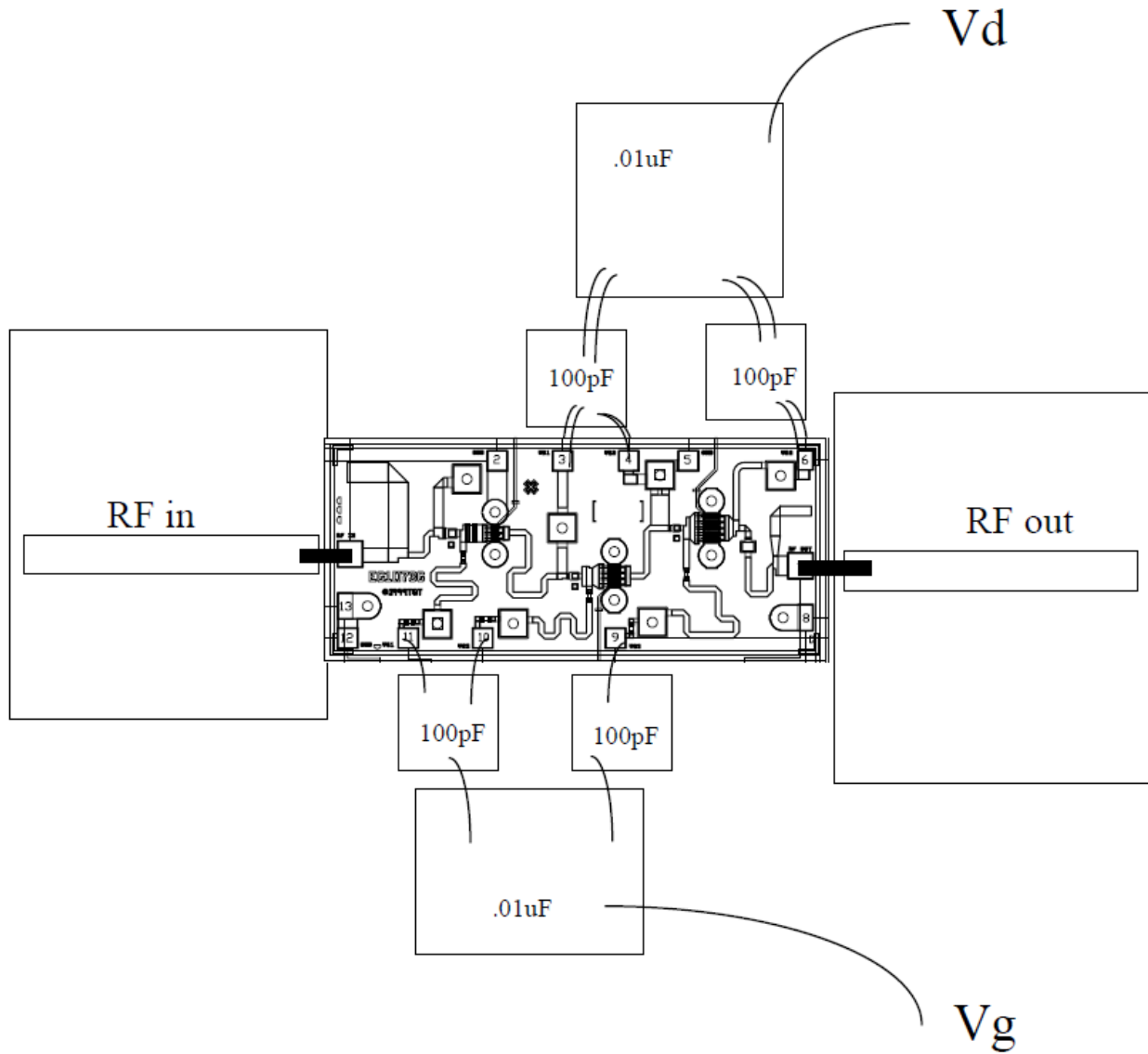
Notes:

- Measured from channel to chip backside.
- Assumes eutectic attach using 1.5 mil thick 80/20 AuSn mounted to a 20 mil CuMo Carrier at 55°C baseplate temperature. Worst case condition with no RF applied, 100% of DC power is dissipated.

Median Lifetime

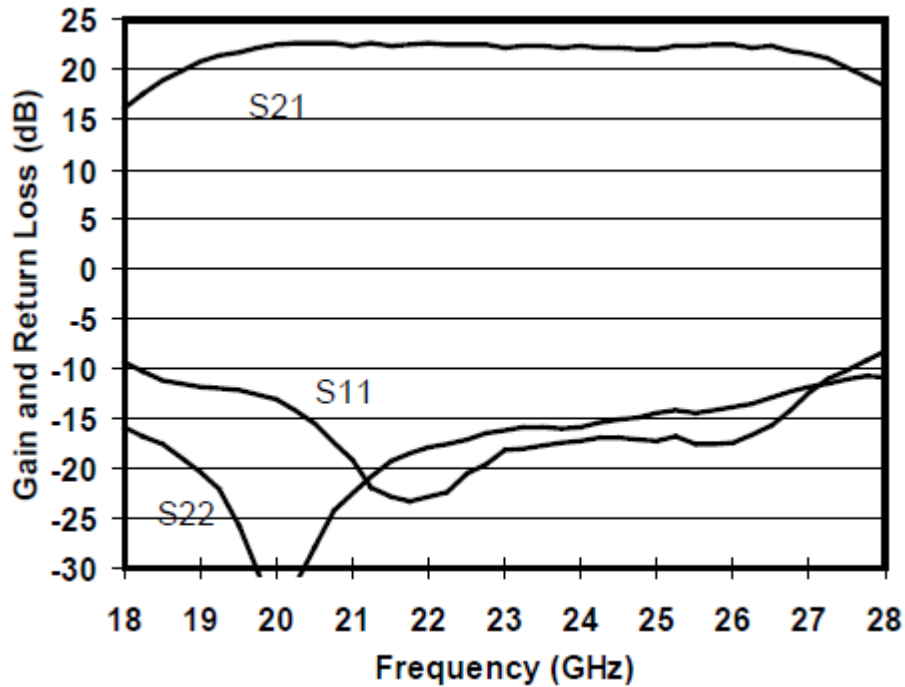


Chip Assembly and Bonding Diagram

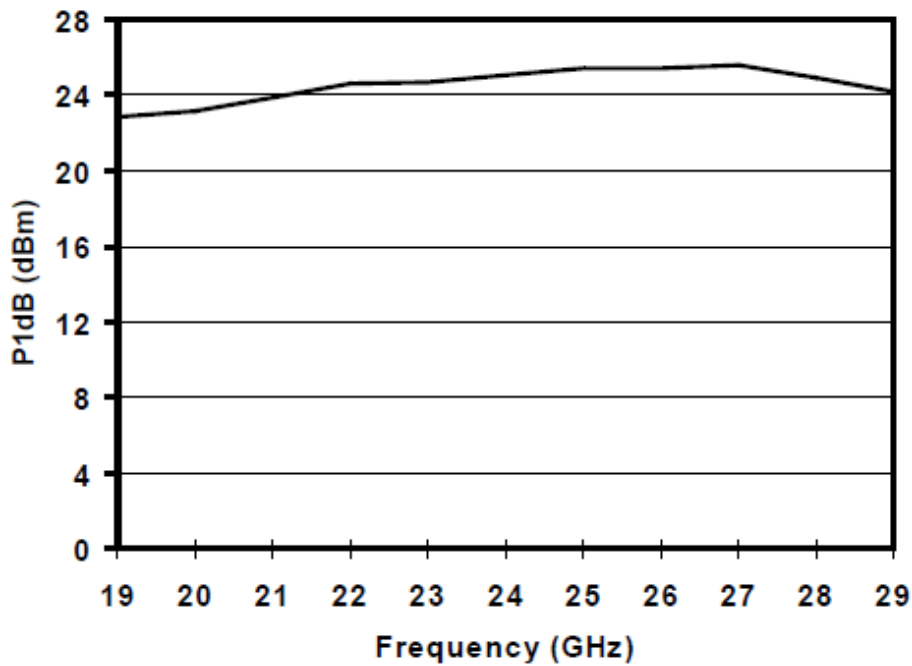


Performance Plots

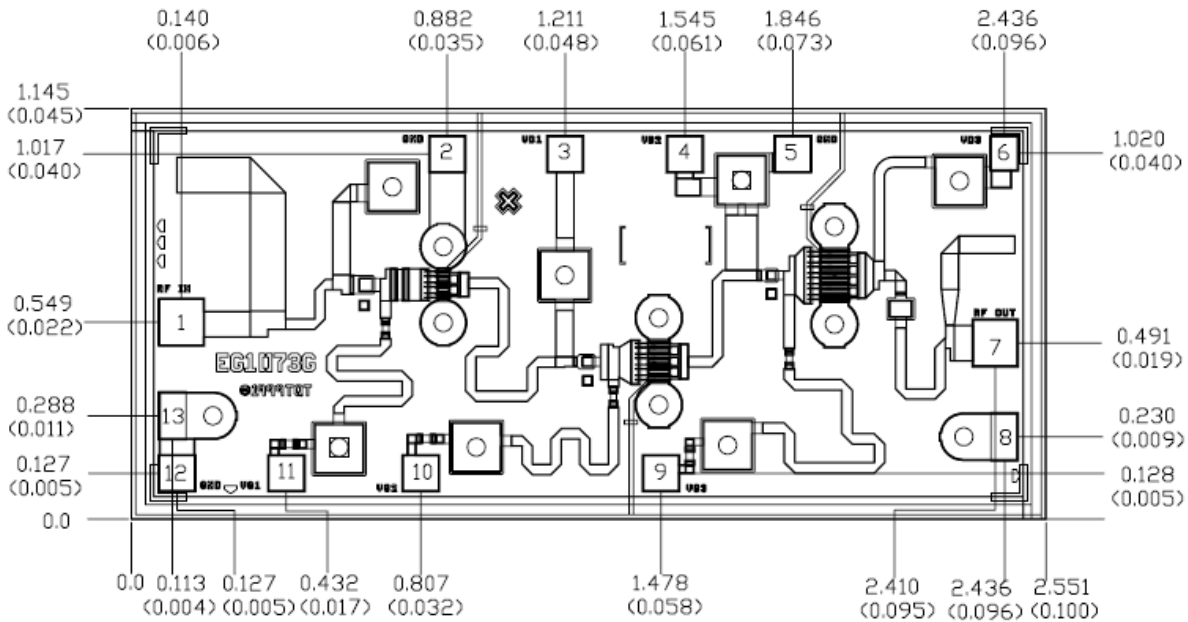
Gain and Return Loss vs. Frequency



P1dB vs. Frequency



Mechanical Characteristics



Units: millimeters (inches)

Thickness: 0.1016 (0.004)

Chip edge to bond pad dimensions are shown to center of bond pad

Chip size tolerance: +/- 0.051 (0.002)

Bond Pad #1 (RF Input)	0.130 x 0.135 (0.005 x 0.005)
Bond Pad #2 (GND)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #3 (VD1)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #4 (VD2)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #5 (GND)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #6 (VD3)	0.081 x 0.100 (0.003 x 0.004)
Bond Pad #7 (RF Output)	0.130 x 0.135 (0.005 x 0.005)
Bond Pad #8 (GND)	0.078 x 0.136 (0.003 x 0.005)
Bond Pad #9 (VG3)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #10 (VG2)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #11 (VG1)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #12 (GND)	0.105 x 0.105 (0.004 x 0.004)
Bond Pad #13 (GND)	0.105 x 0.105 (0.004 x 0.004)

Notes:

1. All dimensions are in millimeters (inches). Angles are in degrees.

Assembly Process Notes

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300°C for 30 sec.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Discrete FET devices with small pad sizes should be bonded with 0.0007-inch wire.
- Maximum stage temperature is 200°C.

Product Compliance Information

ESD Sensitivity Ratings



Caution! ESD-Sensitive Device

ESD Rating: TBD
Value: TBD
Test: Human Body Model (HBM)
Standard: JEDEC Standard JESD22-A114

ECCN

US Department of Commerce EAR99

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